Substitute i	for form 14	149A/PTO				Complete if Known				
		SIID	PLEMEN	ΙΤΛΙ		Application Number 10/		0/664,436		
INFO	RMATI				ATEMENT BY			519 eptember 17, 2003		
1141 01			PLICAN		AILMLMI DI					
		AI.	LICAN					ruo FUJII et al.		
						Group Art Unit 179				
						Examiner Name Par		ul Sang Hwa Hyun		
Sheet	1	T	of 1					62/06180		
'					U.S. PATENT	DOCUMENTS				
Examiner Initials	Cite#		DOCUMENT NUMBER		PATENTEE	ISSUE/PUBLICA TION DATE (mm/dd/yyyy)	CLASS	SUB CLASS		Filing Date if Appropriate
	(1)	6,7	16,002	B2	Higashino	04/06/2004	417	413.2		
	(2)	6,4	6,447,661		Chow et al.	09/10/2002	204	453		
	(3)	7,1	7,192,559		Chow et al.	03/20/2007	422	100		
	(4)	6,8	6,838,055		Sando et al.	01/04/2005	422	100		
	(5)	6,7	6,734,424		Lennon et al.	05/11/2004	250	288		
	(6)	2004/	2004/0200724		Fujii et al.	10/14/2004	204	601		
	(7)	2002/0172969		A1	Burns et al.	11/21/2002	435	6		
	(8)	2005/0247866		A1	Plewa et al.	11/10/2005	250	251		
	(9)	2002/0042125		A1	Petersen et al.	04/11/2002	435	287.2		
				I	FOREIGN PATE	NT DOCUMENTS				
Examine r Initials	Cite #	O F F C	F F I NUM		C O D E	PUBLICATION DATE (mm/dd/yyyy)		TRANSLATION Yes No		
	(10)	JP			A1	07/31/2002		ABSTRACT ONLY		
	(11)	JP	3120466		B2	10/20/2000		X		
Examiner Initials		Includ	de name of the	author (in	CAPITAL LETTERS), title of	ATURE DOCUMEN the article (when appropriate), titl ne-issue number(s), publisher, city	e of the item (b		al, seri:	al, symposiur

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with the next communication to applicant.

DA1 442590v.1